

TranElectric

**IRFC9034
Die for Hexfet®**

Die Specification

General description :

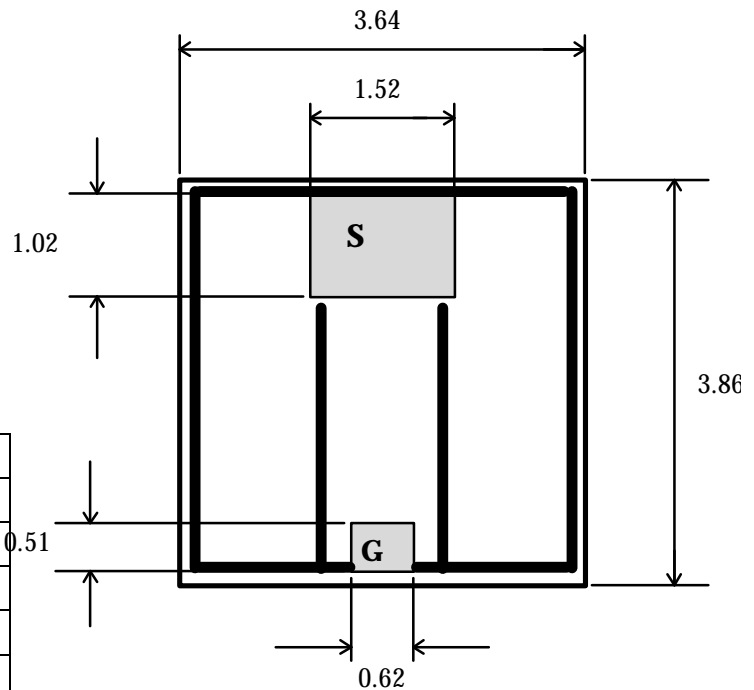
Hexfet® power MOSFET P-channel die with the following features:

- Dynamic dv/dt rating**
- * Ease of paralleling**
- * Repetitive avalanche rated**
- * Fast switching**

Mechanical Characteristic:

Silicon Chip

Dimension (mm):	3.64*3.86
Dimension (mil):	144*152
Thickness:	0.51
Metallization:	Al
Recommended wire(mm):	0.30
Recommended wire(mil):	12



Type	Vds	Rds(on) Vgs=10V	Idss @Ids	Vgs(th) Vds=Vgs, Id=250mkA
IRFC9034	-60V	0.140 Ohms	250 mA	2.0V ... 4.0V

Typical device : IRF9Z34 (in TO-220AB)

Absolut Maximum Rating

	Parameter	Max.	Units
I_D , $T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS}=-10\text{V}$	-18	A
I_D , $T_C=100^\circ\text{C}$	Continuous Drain Current $V_{GS}=-10\text{V}$	-13	
I_{DM}	Pulsed Drain Current ❶	-72	
P_D , $T_C=25^\circ\text{C}$	Power Dissipation	88	W
	Linear Derating Factor	0.59	W/°C
V_{GS}	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy ❷	370	mJ
IAR	Avalanche Current	-18	A
EAR	Repetitive Avalanche Energy ❶	8.8	mJ
dv/dt	Peak Diode Recovery dv/dt ❸	-4.5	V/ns
T_J , T_{STG}	Operating Junction and Storage Temperature Range	-55 to +175	°C

Electrical Characteristics, $T_J=25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	-60			V	$V_{GS}=0$, $I_D=-250\mu\text{A}$
$\Delta V_{(BR)}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.060		V/°C	25°C , $I_D=-1\text{mA}$
$R_{(DS)on}$	Static Drain-to-Source On-Resistance			0.14	Ω	$V_{GS}=-10\text{V}$, $I_D=-11\text{A}$ ❹
$V_{GS(th)}$	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$
g_{fs}	Forward Transconductance	5.9			S	$V_{DS}=-25\text{V}$, $I_D=-11\text{A}$
I_{DSS}	Drain-to-Source Leakage Current			-100	μA	$V_{DS}=-60\text{V}$, $V_{GS}=0\text{V}$
				-500	μA	$V_{DS}=-48\text{V}$, $V_{GS}=0\text{V}$, $T_J=150^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Current			100	nA	$V_{GS}=20\text{V}$
	Gate-to-Source Reverse Current			-100	nA	$V_{GS}=-20\text{V}$
Q_g	Total Gate Charge			34	nC	$V_{GS}=-10\text{V}$
Q_{gs}	Gate-to-Source Charge			9.9	nC	$V_{DS}=-48\text{V}$
Q_{gd}	Gate-to-Drain Charge			16	nC	$I_D=-18\text{A}$ ❹
$t_{d(on)}$	Turn-On Delay Time		18		ns	$V_{DD}=-30\text{V}$ $I_D=-18\text{A}$ $R_G=12\Omega$ $R_D=1.5\Omega$ ❹
t_r	Rise Time		120			
$t_{d(off)}$	Turn-Off Delay Time		20			
t_f	Fall Time		58			
L_D	Internal Drain Inductance		4.5		nH	Between lead, 6 mm from package and center of die contact
L_S	Internal Source Inductance		7.5			
C_{iss}	Input Capacitance		1100		pF	$V_{GS}=0$ $V_{DS}=-25\text{V}$ $f=1.0\text{MHz}$
C_{oss}	Output Capacitance		620			
C_{rSS}	Reverse Transfer Capacitance		100			

Source-Drain Ratings and Characteristics

	Parameter	Min	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)			-18	A	
I_{SM}	Pulsed Source Current (Body Diode) ❶			-72	A	
V_{SD}	Diode Forward Voltage			-6.3	V	$I_S=-18\text{A}$, $V_{GS}=0\text{V}$, $T_J=25^\circ\text{C}$ ❹
t_{rr}	Reverse Recovery Time		100	200	ns	$T_J=25^\circ\text{C}$, $I_F=-18\text{A}$,
Q_{rr}	Reverse Recovery Charge		0.28	0.52	μC	$di/dt=100\text{A}/\mu\text{s}$ ❹

Thermal resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case			1.7	W/°C
$R_{\theta JC}$	Case-to-Sink, Flat, Greased Surface		0.50		
$R_{\theta JC}$	Junction-to-Ambient			62	

❶ Reprtitive rating ; pulse width limited by max. junction temperature .

 ❷ Starting $T_J=25^\circ\text{C}$, $L=1.3\text{mH}$, $R_G=25\Omega$, $I_{AS}=-18\text{A}$, $V_{DD}=-25\text{V}$.

 ❸ $I_{SD}\leq-18\text{A}$, $di/dt\leq 170\text{A}/\mu\text{s}$, $V_{DD}\leq V_{(BR)DSS}$, $T_J\leq 175^\circ\text{C}$.

 ❹ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$